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TABLE OF CONTENTS

A Self-consistent Model to Estimate NBTI Degradation and a Comprehensive On-line System Lifetime Enhancement Technique.....	1
<i>G. Karakontantis, C. Augustine, K. Roy</i>	
Predictive Error Detection by On-line Aging Monitoring.....	7
<i>J.C. Vazquez, V. Champac, A.M. Ziesemer Jr., R. Reis, J. Semiao, I.C. Teixeira, M.B. Santos, J.P. Teixeira</i>	
Temperature Dependence of NBTI Induced Delay.....	13
<i>S. Khan, S. Hamdioui</i>	
Aging Test Strategy and Adaptive Test Scheduling for SoC Failure Prediction.....	19
<i>H. Yi, T. Yoneda, M. Inoue, Y. Sato, S. Kajihara, H. Fujiwara</i>	
Analysis of Root Causes of Alpha Sensitivity Variations on Microprocessors Manufactured using Different Cell Layouts.....	25
<i>P. Rech, M. Grosso, F. Melchiori, D. Loparco, D. Appello, L. Dilillo, A. Paccagnella, M.S. Reorda</i>	
Evaluating Transient-Fault Effects on Traditional C-element's Implementations.....	31
<i>R.P. Bastos, G. Sicard, F. Kastensmidt, M. Renaudin, R. Reis</i>	
Probabilistic Methods for the Impact of an SET in Combinational Logic.....	37
<i>S. Gangadhar, S. Tragoudas</i>	
Analysis of On-Line Self-Testing Policies for Real-Time Embedded Multiprocessors in DSM Technologies.....	43
<i>O. Heron, J. Guilhemang, N. Ventroux, A. Giulieri</i>	
Distributed Online Software Monitoring of Manycore Architectures	50
<i>E. Faure, M. Benabdenbi, F. Pecheux</i>	
SBST for On-Line Detection of Hard Faults in Multiprocessor Applications Under Energy Constraints	56
<i>A. Merentitis, D. Margaris, N. Kranitis, A. Paschalidis, D. Gizopoulos</i>	
An Analog VLSI Multilayer Perceptron and its Application Towards Built-In Self-Test in Analog Circuits	62
<i>D. Maliuik, H. Stratigopoulos, Y. Makris</i>	
Built-In Performance Monitoring of Mixed-Signal/RF Front Ends Using Real-Time Parameter Estimation	68
<i>S.K. Devarakond, S. Sen, A. Banerjee, V. Natarajan, A. Chatterjee</i>	
Wavelet Analysis of Measurements for On-Line Testing Analog & Mixed-Signal Circuits	74
<i>M.G. Dimopoulos, A.D. Spyronasios, A.A. Hatzopoulos</i>	
A Framework to Support the Design of COTS-based Reliable Space Computers for On-Board Data Handling.....	79
<i>S. Campagna, M. Violante</i>	
Checkpointing Virtual Machines Against Transient Errors.....	85
<i>L. Wang, Z. Kalbarczyk, R.K. Iyer, A. Iyengar</i>	
Qualification and Relieving Testing for Space Applications Applied to the Agilent G-Link Components	91
<i>M. Pignol, F. Malou, C. Aicardi</i>	
Panel: SER Standards: Where We Are? What's Next?.....	97
<i>E. Ibe, M. Nicolaidis, D. Alexandrescu, R. Baumann, A. Bougerol, E. Ibe, S. Rezgui, C. Slayman</i>	
Configurable Serial Fault-Tolerant Link for Communication in 3D Integrated Systems.....	98
<i>V. Pasca, L. Anghel, C. Rusu, M. Benabdenbi</i>	
RILM: Reconfigurable Inter-Layer Routing Mechanism for 3D Multi-Layer Networks-on-Chip.....	104
<i>C. Rusu, L. Anghel, D. Avresky</i>	
An FPGA-Based Fail-Soft System with Adaptive Reconfiguration.....	110
<i>R. Noji, S. Fujie, Y. Yoshikawa, H. Ichihara, T. Inoue</i>	
Thermal Coupling in ICs: Applications to the Test and Characterization of Analogue and RF Circuits.....	116
<i>J. Altet, D. Mateo, E. Aldrete-Vidrio</i>	
Radiation Effects on Programmable Analog Devices and Mitigation Techniques	117
<i>T.R. Balen, M. Lubaszewski</i>	
Concepts for Fault Tolerant Sensor Systems.....	118
<i>A. Richardson</i>	
Cross-BIC Architecture for Single and Multiple SEU Detection Enhancement in SRAM Memories.....	119
<i>S.A. Bota, G. Torrens, B. Alorda, J. Verd, J. Segura</i>	
Programmable Restricted SEC Codes to Mask Permanent Faults in Semiconductor Memories.....	125
<i>S. Evain, Y. Bonhomme, V. Gheman</i>	

A Bit Level Area Aware Cache-Based Architecture for Memory Repairs	132
<i>N. Axelos, K. Pekmestzi</i>	
A Software-Based Self-Test Methodology for In-System Testing of Processor Cache Tag Arrays	137
<i>G. Theodorou, N. Kranitis, A. Paschalidis, D. Gizopoulos</i>	
An On-line Fault Detection Technique Based on Embedded Debug Features	143
<i>M. Grosso, M.S. Reorda, M. Portela-Garcia, M. Garcia-Valderas, C. Lopez-Ongil, L. Entrena</i>	
A Partitioning Approach to Improve Reconfigurable Neuron-inspired Online BIST	149
<i>A. Shahabi, S.B. Hosseini, H. Sohofi, Z. Navabi</i>	
Selecting State Variables for Improved On-Line Testability Through Output Response Comparison of Identical Circuits	155
<i>i. Pomeranz, S.M. Reddy</i>	
A Method for Detecting Resistive Opens in Buses	161
<i>J. Rius</i>	
A New Framework for the Automatic Insertion of Mitigation Structures in Circuit Netlists.....	164
<i>N. Battezzati, D. Serrone, M. Violante</i>	
Application Dependent FPGA Testing Method Using Compressed Deterministic Test Vectors	166
<i>M. Rozkovec, J. Jenicek, O. Navak</i>	
Fully Distributed Initialization Procedure for a 2D-Mesh NoC, Including Off-Line BIST and Partial Deactivation of Faulty Components	168
<i>Z. Zhang, A. Greiner, M. Benabdenbi</i>	
Improving Fault Handling Software Techniques.....	171
<i>P. Gawkowski, T. Rutkowski, J. Sosnowski</i>	
Investigating the Use of BICS to Detect Resistive-Open Defects in SRAMs	174
<i>R. Chipana, L. Bolzani, F. Vargas, J. Semiao, J. Rodriguez-Andina, I. Teixeira, P. Teixeira</i>	
Self-Checking Arithmetic Logic Unit with Duplicated Outputs	176
<i>V. Ocheretny</i>	
Online Fault Testing of Reversible Logic Using Dual Rail Coding.....	178
<i>N. Farazmand, M. Zamani, M.B. Tahoori</i>	
Reconfigurable Low-Power Concurrent Error Detection in Logic Circuits.....	180
<i>S. Almukhaizim, S. Bunian, O. Sinanoglu</i>	
Robust Cryptographic Ciphers with On-line Statistical Properties Validation	182
<i>A. Vaskova, C. Lopez-Ongil, A. Jimenez-Horas, E.S. Millan, L. Entrena</i>	
Trustworthy Computing in a Multi-Core System Using Distributed Scheduling	185
<i>D. McIntyre, F. Wolff, C. Papachristou, S. Bhunia</i>	
3D Integration: Circuit Design, Test, and Reliability Challenges.....	188
<i>N. Minas, I. De Wolf, E.J. Marinissen, M. Stucchi, H. Oprins, A. Mercha, G. Van Der Plaas, D. Velenis, P. Marchal</i>	
Interconnect Built-In Self-Repair and Adaptive-Serialization (I-BIRAS) for 3D Integrated Systems.....	189
<i>M. Nicolaidis, V. Pasca, L. Anghel</i>	
Test and Reliability Concerns for 3D-ICs (Paper Not Available).....	190
<i>Y. Zorian</i>	
Evaluation of Concurrent Error Detection Techniques on the Advanced Encryption Standard	191
<i>K. Bousselam, G. Di Natale, M.L. Flottes, B. Rouzeyre</i>	
Key Randomization using a Power Analysis Resistant Deterministic Random Bit Generator	197
<i>P. Duplys, E. Bohl, W. Rosenstiel</i>	
How to Flip a Bit?	203
<i>M. Agoyan, J. Duterre, A. Mirbaha, D. Naccache, A. Ribotta, A. Tria</i>	
Robust FSMs for Cryptographic Devices Resilient to Strong Fault Injection Attacks.....	208
<i>Z. Wang, M. Karpovsky</i>	
On-Line Detection of Random Voltage Perturbations In Buses With Multiple-Threshold Receivers	214
<i>M.N. Skoufis, S. Tragoudas</i>	
Design of Embedded Constant Weight Code Checkers Based on Averaging Operations	220
<i>S. Tarnick</i>	
On-line Testing of Bundled-Data Asynchronous Handshake Protocols.....	226
<i>S. Zeidler, A. Bystrov, M. Krstic, R. Kraemer</i>	
Reducing the Area Overhead of TMR-Systems by Protecting Specific Signals	233
<i>M. Augustin, M. Gossel, R. Kraemer</i>	
Robust Detection of Soft Errors Using Delayed Capture Methodology	239
<i>V. Prasanth, V. Singh, R. Parekhji</i>	
Timing Error Tolerance in Nanometer ICs.....	245
<i>S. Valadimas, Y. Tsiatouhas, A. Arapoyanni</i>	

Error Resilient Video Encoding Using Block-Frame Checksums 251

J.W. Wells, J. Natarajan, A. Chatterjee

Author Index